

Date Created : 2008/10/09  
Date Issued On : 2008/11/13  
PCN# : Q1081305-A

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Phone:

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Phone:

Implementation of change:  
Expected 1st Device Shipment Date: 2008/12/15

Earliest Year/Work Week of Changed Product: 0851

Change Type Description: New Assembly Site Location/Qualification

Description of Change (From): PDIP08 assembly at Subcon Hana Thailand.

Description of Change (To): New subcon AIC to take over PDIP08 assembly from Subcon Hana Thailand.

Reason for Change : Transfer PDIP08 assembly site from Subcon Hana Thailand to Subcon AIC

Qual/REL Plan Numbers : Q20080158

Qualification :

AIC is passed the rel test and qualified for GFPS 8DIP assembly and test.

**Results/Discussion for Qual Plan Number - Q20080158**

Test: (Aging Bake (Obsoleted))   Conditions: 93%RH, 60C   Standard: Modified NEMI				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AAABAKE	FSDM0365RN	500-HOURS	0/4	
		1000-HOURS	0/4	
Q20080158ABABAKE		500-HOURS	0/4	
		1000-HOURS	0/4	
Q20080158ACABAKE		1000-HOURS	0/4	

  

Test: (Charged Device Model ESD)   Conditions: 1000V   Standard: JESD22-C101				
Lot	Device	Setpoint	Result	Failure Code

Q20080158AACDM	FSDM0365RN		0/3	
Q20080158ABCDM			0/3	
Q20080158ACCDM			0/3	
<b>Test: (High Temperature Op Life)   Conditions: 125C   Standard:</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AAHTOL	FSDM0365RN	168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158ABHTOL		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158AHTOL		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
<b>Test: (High Temperature Reverse Bias)   Conditions: 125C, 520V   Standard: JESD22-A108</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AAHTRB	FSDM0365RN	168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158ABHTRB		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158ACHTRB		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
<b>Test: (High Temperature Storage Life)   Conditions: 150C   Standard: JESD22-A103</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AAHTSL	FSDM0365RN	168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158ABHTSL		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158AHTSL		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
<b>Test: (Storage Bake)   Conditions: Ambient   Standard: Modified NEMI</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AASBAKE	FSDM0365RN	500-HOURS	0/4	
		1000-HOURS	0/4	
Q20080158ABSBAKE		500-HOURS	0/4	
		1000-HOURS	0/4	
Q20080158ACSBAKE		500-HOURS	0/4	
		1000-HOURS	0/4	
<b>Test: (Temperature Cycle)   Conditions: -55C, 85C   Standard: Modified NEMI</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AATMCL4	FSDM0365RN	500-CYCLES	0/4	
		1000-CYCLES	0/4	
Q20080158ABTMCL4		500-CYCLES	0/4	
		1000-CYCLES	0/4	
<b>Test: (Temperature Cycle)   Conditions: -65C, 150C   Standard: JESD22-A104</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158AATMCL1	FSDM0365RN	200-CYCLES	0/77	
		500-CYCLES	0/77	
Q20080158ABTMCL1		200-CYCLES	0/77	
		500-CYCLES	0/77	
Q20080158ACTMCL1		200-CYCLES	0/77	
		500-CYCLES	0/77	
<b>Test: (Temperature Cycle)   Conditions: AmbientC, 85C   Standard: Modified NEMI</b>				
Lot	Device	Setpoint	Result	Failure Code
Q20080158ACTMCL4	FSDM0365RN	500-CYCLES	0/4	
		1000-CYCLES	0/4	
<b>Test: (Temperature Humidity Biased Test)   Conditions: 85%RH, 85C, 10V   Standard: JESD22-A101</b>				
Lot	Device	Setpoint	Result	Failure Code

Q20080158AATHBT	FSDM0365RN	168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158ABTHBT		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	
Q20080158ACTHBT		168-HOURS	0/77	
		500-HOURS	0/77	
		1000-HOURS	0/77	

Product Id Description :

Affected FSIDs :

FSDH321	FSDL0165RN	FSDM0265RNC
FSDM0365RN	FSDM311A	FSDM311
FSQ0165RN	FSQ0265RN	FSQ0365RN
FSQ100	FSQ110	FSQ211
FSQ221	FSQ311	FSQ321